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**Non-destructive testing —  
Characterization and verification of  
ultrasonic test equipment —**

**Part 2:  
Probes**

*Essais non destructifs — Caractérisation et vérification de  
l'appareillage de contrôle par ultrasons —*

*Partie 2: Traducteurs*

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# Contents

	Page
<b>Foreword</b>	<b>v</b>
<b>1 Scope</b>	<b>1</b>
<b>2 Normative references</b>	<b>1</b>
<b>3 Terms and definitions</b>	<b>1</b>
<b>4 Symbols</b>	<b>3</b>
<b>5 General requirements of conformity</b>	<b>4</b>
<b>6 Technical information for probes</b>	<b>5</b>
6.1 General	5
6.2 Probe data sheet	5
6.3 Probe test report	5
<b>7 Test equipment</b>	<b>7</b>
7.1 Electronic equipment	7
7.2 Test blocks and other equipment	7
<b>8 Performance requirements for probes</b>	<b>15</b>
8.1 Physical aspects	15
8.1.1 Procedure	15
8.1.2 Acceptance criterion	15
8.2 Pulse shape, amplitude and duration	15
8.2.1 Procedure	15
8.2.2 Acceptance criterion	16
8.3 Frequency spectrum and bandwidth	17
8.3.1 Procedure	17
8.3.2 Acceptance criteria	17
8.4 Pulse-echo sensitivity	17
8.4.1 Procedure	17
8.4.2 Acceptance criterion	18
8.5 Distance-amplitude curve	18
8.5.1 General	18
8.5.2 Procedure	18
8.5.3 Acceptance criterion	20
8.6 Beam parameters for immersion probes	20
8.6.1 General	20
8.6.2 Beam profile — Measurements performed directly on the beam	21
8.6.3 Beam profile — Measurements made using an automated scanning system	28
8.7 Beam parameters for straight-beam single-transducer contact probes	30
8.7.1 General	30
8.7.2 Beam divergence and side lobes	31
8.7.3 Squint angle and offset for straight-beam probes	32
8.7.4 Focal distance (near field length)	33
8.7.5 Focal width	33
8.7.6 Length of the focal zone	34
8.8 Beam parameters for angle-beam single-transducer contact probes	34
8.8.1 General	34
8.8.2 Index point	34
8.8.3 Beam angle and beam divergence	35
8.8.4 Squint angle and offset for angle-beam probes	38
8.8.5 Focal distance (near field length)	41
8.8.6 Focal width	42
8.8.7 Length of the focal zone	42
8.9 Beam parameters for straight-beam dual-transducer contact probes	43
8.9.1 General	43
8.9.2 Delay line delay path	43

8.9.3	Focal distance .....	43
8.9.4	Axial sensitivity range (focal zone).....	43
8.9.5	Lateral sensitivity range (focal width).....	44
8.10	Beam parameters for angle-beam dual-transducer contact probes.....	45
8.10.1	General.....	45
8.10.2	Index point.....	45
8.10.3	Beam angle and profiles.....	45
8.10.4	Wedge delay path .....	46
8.10.5	Distance to sensitivity maximum (focal distance).....	46
8.10.6	Axial sensitivity range (length of the focal zone).....	46
8.10.7	Lateral sensitivity range (focal width).....	46
8.11	Crosstalk.....	47
8.11.1	Procedure.....	47
8.11.2	Acceptance criterion.....	47
<b>Annex A (normative) Calculation of the near field length of non-focusing probes</b> .....		<b>48</b>
<b>Annex B (informative) Calibration block for angle-beam probes</b> .....		<b>51</b>
<b>Annex C (informative) Determination of delay line and wedge delays</b> .....		<b>55</b>
<b>Bibliography</b> .....		<b>56</b>

## Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see [www.iso.org/patents](http://www.iso.org/patents)).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see [www.iso.org/iso/foreword.html](http://www.iso.org/iso/foreword.html).

This document was prepared by Technical Committee ISO/TC 135, *Non-destructive testing*, Subcommittee SC 3, *Ultrasonic testing*, in collaboration with the European Committee for Standardization (CEN) Technical Committee CEN/TC 138, *Non-destructive testing*, in accordance with the Agreement on technical cooperation between ISO and CEN (Vienna Agreement).

A list of all parts in the ISO 22232 series can be found on the ISO website.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at [www.iso.org/members.html](http://www.iso.org/members.html).



# Non-destructive testing — Characterization and verification of ultrasonic test equipment —

## Part 2: Probes

### 1 Scope

This document specifies the characteristics of probes used for non-destructive ultrasonic testing in the following categories with centre frequencies in the range of 0,5 MHz to 15 MHz, focusing or without focusing means:

- a) single- or dual-transducer contact probes generating longitudinal and/or transverse waves;
- b) single-transducer immersion probes.

Where material-dependent ultrasonic values are specified in this document they are based on steels having a sound velocity of  $(5\ 920 \pm 50)$  m/s for longitudinal waves, and  $(3\ 255 \pm 30)$  m/s for transverse waves.

This document excludes periodic tests for probes. Routine tests for the verification of probes using on-site procedures are given in ISO 22232-3.

If parameters in addition to those specified in ISO 22232-3 are to be verified during the probe's life time, as agreed upon by the contracting parties, the procedures of verification for these additional parameters can be selected from those given in this document.

This document also excludes ultrasonic phased array probes, therefore see ISO 18563-2.

### 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 5577, *Non-destructive testing — Ultrasonic testing — Vocabulary*

ISO 7963, *Non-destructive testing — Ultrasonic testing — Specification for calibration block No. 2*

ISO 22232-1, *Non-destructive testing — Characterization and verification of ultrasonic test equipment — Part 1: Instruments*

ISO/IEC 17050-1, *Conformity assessment — Supplier's declaration of conformity — Part 1: General requirements*

### 3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 5577 and the following apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- ISO Online browsing platform: available at <https://www.iso.org/obp>
- IEC Electropedia: available at <http://www.electropedia.org/>